



**International  
Standard**

**ISO 22514-7**

**Statistical methods in process  
management — Capability and  
performance —**

**Part 7:  
Capability of measurement  
processes**

**AMENDMENT 1**

*Méthodes statistiques dans la gestion de processus — Aptitude et  
performance —*

*Partie 7: Aptitude des processus de mesure*

*AMENDEMENT 1*

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This document was prepared by Technical Committee ISO/TC 69, *Applications of statistical methods*, Subcommittee SC 4, *Applications of statistical methods in product and process management*.

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# Statistical methods in process management — Capability and performance —

## Part 7: Capability of measurement processes

### AMENDMENT 1

#### 6.2.3.3

Replace the last row in Table 6 by the following:

	$u_{TA} =  T - 20\text{ °C}  \cdot u_{\alpha} \cdot l$ <p>where</p> <p><math>T</math> is the average temperature during the measurement;</p> <p><math>u_{\alpha}</math> is the uncertainty on the coefficient of expansion;</p> <p><math>l</math> is the observed value for length measurement.</p>
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#### 6.2.3.6.3

Replace the first formula by the following:

$$u_{TA} = |T - 20\text{ °C}| \cdot u_{\alpha} \cdot l$$

9.2

Replace the fourth and fifth paragraph by the following:

The capability of a measurement system can be expressed as a capability index  $C_{MS}$ .

$$C_{MS} = C_{MS_{min}} \cdot Q_{MS_{min}} \cdot \frac{(U-L)}{2 \cdot k \cdot u_{MS}} = \frac{4}{3} \cdot 0,15 \cdot \frac{(U-L)}{2 \cdot k \cdot u_{MS}} = 0,2 \cdot \frac{(U-L)}{2 \cdot k \cdot u_{MS}}$$

The capability of a measurement process can be expressed as a capability index  $C_{MP}$ .

$$C_{MP} = C_{MP_{min}} \cdot Q_{MP_{min}} \cdot \frac{(U-L)}{2 \cdot k \cdot u_{MP}} = \frac{4}{3} \cdot 0,30 \cdot \frac{(U-L)}{2 \cdot k \cdot u_{MP}} = 0,4 \cdot \frac{(U-L)}{2 \cdot k \cdot u_{MP}}$$

9.3

Replace the fifth and sixth paragraph up to before the formula with the following:

There are several ways to estimate the manufacturing process dispersion  $\Delta$  in the following priority:

- a) manufacturing process dispersion determined according to ISO 22514-1 and ISO 22514-2
- b) manufacturing process dispersion calculated from the experiment described in clause 6.2.3.2
- c) manufacturing process spread and process location estimated from historical data of similar processes

See details in the following paragraphs.

The manufacturing process dispersion is preferably determined according to ISO 22514-1 and ISO 22514-2 using a minimum sample size of 100.

Replace the two paragraphs after Figure 5 by the following:

If an upper one-sided specification limit is given, the capability indices and performance ratios are calculated as:

$$C_{MS} = 0,2 \cdot \frac{C_p \cdot \Delta_U}{k \cdot u_{MS}} \quad C_{MP} = 0,4 \cdot \frac{C_p \cdot \Delta_U}{k \cdot u_{MP}}$$

$$Q_{MS} = \frac{k \cdot u_{MS}}{C_p \cdot \Delta_U} \quad Q_{MP} = \frac{k \cdot u_{MP}}{C_p \cdot \Delta_U}$$

If a lower one-sided specification limit is given, the capability indices and performance ratios are calculated as:

$$C_{MS} = 0,2 \cdot \frac{C_p \cdot \Delta_L}{k \cdot u_{MS}} \quad C_{MP} = 0,4 \cdot \frac{C_p \cdot \Delta_L}{k \cdot u_{MP}}$$

$$Q_{MS} = \frac{k \cdot u_{MS}}{C_p \cdot \Delta_L} \quad Q_{MP} = \frac{k \cdot u_{MP}}{C_p \cdot \Delta_L}$$